



SpecMetrix[®] Enhanced Lab System

Enhanced Lab Coating Thickness Measurement Systems

The SpecMetrix Enhanced Lab Coating Thickness Measurement System delivers a higher standard for non-contact, non-destructive and real-time absolute thickness measurement data for applied coatings and coated layers.

Designed to streamline QA processes, the SpecMetrix Enhanced Lab System provides offline sample testing in lab environments combined with periodic in-line coating process validation capabilities, which can help prevent thousands of feet of defective material.

The SpecMetrix Enhanced Lab System optimizes coating processes and quality control by improving inspections on multiple substrates and is well-suited for pilot lines, test facilities and high changeover environments.



Features & benefits:

- **Flexible and Fast**
Modular design enables faster offline or select in-line measurement use.
- **Non-Contact**
Measurements are taken with no harm to coatings or substrate, preserving sample and part integrity.
- **Absolute Thickness Measurement**
Ultra-precise, real-time measurement of coating or layer thickness accelerates sample testing, data collection and QA analysis.
- **Substrate Independent**
Measures coated parts and applied layers over clear, colored or pigmented substrates.
- **Broad Range of Use**
Real-time measurement for single or dual coatings and multiple film layers down to sub-micron levels, wet or dry.
- **Non-Hazardous**
Incorporates exclusive non-radioactive and non-invasive ROI optical measurement.
- **Environmentally Friendly**
Non-destructive testing method helps reduce scrap, rework labor and energy costs.
- **Powerful SpecMetrix Software**
User-friendly software package stores all data to Excel or interfaces to plant networks for SPC analysis.

Options:

SpecMetrix Enhanced Lab System includes multiple lab and In-line accessories.



▲ Periodic in-process measurements via magnetic arm with ruggedized probe.



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Technical Specification:

Measurement Range: 0.3 to 250 microns
(coating thickness)

Accuracy: +/-1% of coating thickness
(nominal)

Measurement Speed: Up to 100 per second

Temperature Range: 0 to 45 °C

Output Metrics: Microns, mils, mg/in², mg/4in²,
g/m², mg/cm², lbs/ream

Operating System: Windows® platform

Manufactured: Made in USA

Certifications: CE SP UL

System Components:

- Processing unit
- Touch screen controls
- Operator input keyboard
- Sample test stand and holder
- Optical probe assembly
- Lab probe
- Ruggedized in-line probe
- Magnetic arm and mounting kit
- NIST traceable thickness standards

Disclaimer

The information contained in this document is liable to modification from time to time in the light of experience and our policy of continuous product development. Check the Industrial Physics website for the latest version.

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